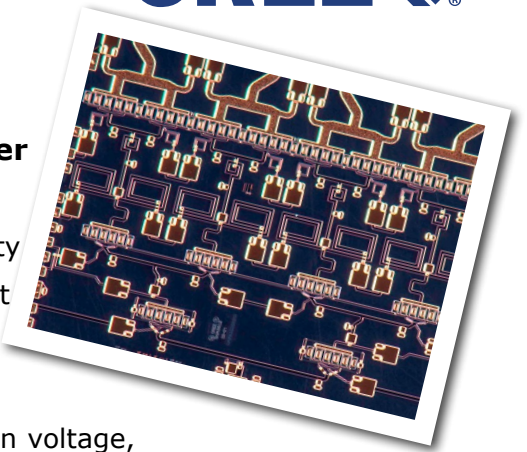


CMPA1D1E030D

30 W, 13.75 - 14.5 GHz, 40 V, GaN MMIC, Power Amplifier

Cree's CMPA1D1E030D is a gallium nitride (GaN) High Electron Mobility Transistor (HEMT) based monolithic microwave integrated circuit (MMIC) on a silicon carbide substrate, using a 0.25 μm gate length fabrication process. GaN-on-SiC has superior properties compared to silicon, gallium arsenide or GaN-on-Si, including higher breakdown voltage, higher saturated electron drift velocity and higher thermal conductivity. GaN HEMTs also offer greater power density and wider bandwidths compared to Si, GaAs, and GaN-on-Si transistors.



Typical Performance Over 13.75-14.5 GHz ($T_c = 25^\circ\text{C}$)

Parameter	13.75 GHz	14.0 GHz	14.5 GHz	Units
Small Signal Gain	27	26	25	dB
P_{SAT} @ $P_{\text{IN}} = 26$ dBm	33	34	30	W
P_{3dB} Backoff @ $P_{\text{IN}} = 20$ dBm	20	20	16	W
PAE @ $P_{\text{IN}} = 26$ dBm	24	23	22	%
PAE @ $P_{\text{IN}} = 20$ dBm	22	21	20	%

Note: All data in this table is based on fixtured, CW performance.

Features

- 27 dB Small Signal Gain
- 30 W Typical P_{SAT}
- Operation up to 40 V
- High Breakdown Voltage
- High Temperature Operation

Applications

- Satellite Communications Uplink

Absolute Maximum Ratings (not simultaneous) at 25 °C

Parameter	Symbol	Rating	Units	Conditions
Drain-source Voltage	V_{DSS}	84	V_{DC}	25 °C
Gate-source Voltage	V_{GS}	-10, +2	V_{DC}	25 °C
Storage Temperature	T_{STG}	-55, +150	°C	
Operating Junction Temperature	T_J	225	°C	
Maximum Forward Gate Current	I_{GMAX}	10	mA	25 °C
Maximum Drain Current ¹	I_{DMAX}	0.6	A	Stage 1, 25 °C
Maximum Drain Current ¹	I_{DMAX}	0.96	A	Stage 2, 25 °C
Maximum Drain Current ¹	I_{DMAX}	2.2	A	Stage 3, 25 °C
Thermal Resistance, Junction to Case ²	$R_{\theta JC}$	1.5	°C/W	85 °C, $P_{DISS} = 94W$
Mounting Temperature (30 seconds)	T_S	320	°C	30 seconds

Note¹ Current limit for long term, reliable operation. Total current when biased from top and bottom drain pads.

Note² Eutectic die attach using 80/20 AuSn mounted to a 20 mil thick CuMoCu carrier.

Electrical Characteristics (Frequency = 13.75 GHz to 14.5 GHz unless otherwise stated; $T_C = 25 °C$)

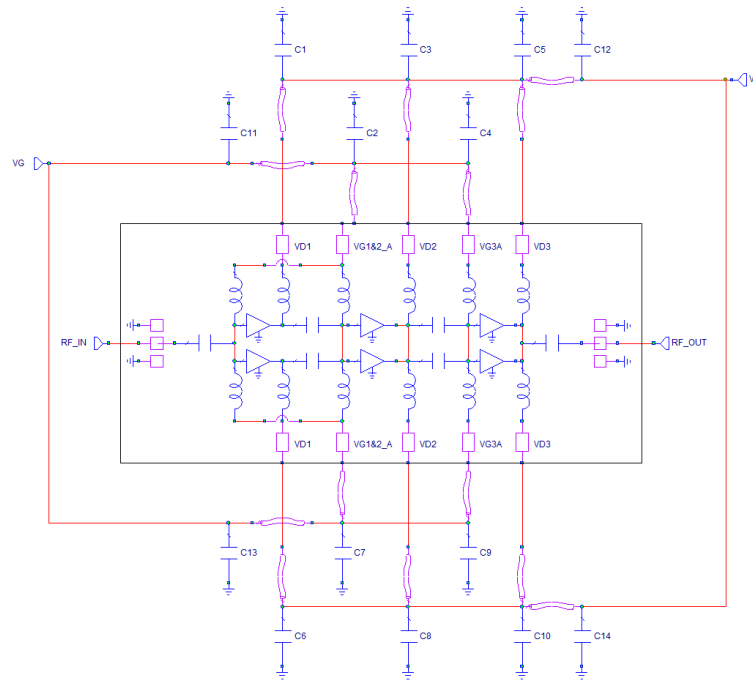
Characteristics	Symbol	Min.	Typ.	Max.	Units	Conditions
DC Characteristics						
Gate Threshold	V_{TH}	-3.8	-2.8	-2.3	V	$V_{DS} = 10 V, I_D = 18.2 mA$
Drain-Source Breakdown Voltage	V_{BD}	84	100	-	V	$V_{GS} = -8 V, I_D = 18.2 mA$
RF Characteristics²						
Small Signal Gain	S21	-	27	-	dB	$V_{DD} = 40 V, I_{DQ} = 300 mA$
Input Return Loss	S11	-	-16	-	dB	$V_{DD} = 40 V, I_{DQ} = 300 mA$
Output Return Loss	S22	-	-9	-	dB	$V_{DD} = 40 V, I_{DQ} = 300 mA$
Power Output	P_{OUT1}	-	50	-	W	$V_{DD} = 40 V, I_{DQ} = 300 mA, CW, P_{IN} = 24 dBm$
Power Output	P_{OUT2}	-	24	-	W	$V_{DD} = 40 V, I_{DQ} = 300 mA, P_{IN} = 18 dBm$
Power Added Efficiency	PAE_1	-	30	-	%	$V_{DD} = 40 V, I_{DQ} = 300 mA, CW, P_{IN} = 24 dBm$
Power Added Efficiency	PAE_2	-	25	-	%	$V_{DD} = 40 V, I_{DQ} = 300 mA, P_{IN} = 18 dBm$
Power Gain	G_p	-	22	-	dB	$V_{DD} = 40 V, I_{DQ} = 300 mA$
Output Mismatch Stress	VSWR	-	5 : 1	-	Ψ	No damage at all phase angles, $V_{DD} = 40 V, I_{DQ} = 300 mA, P_{OUT} = 25W CW$

Notes:

¹ Scaled from PCM data.

² All data pulse tested on-wafer with Pulse Width = 10 μs , Duty Cycle = 0.1%.

Block Diagram Showing Additional Capacitors for Operation Over 13.75 to 14.5 GHz



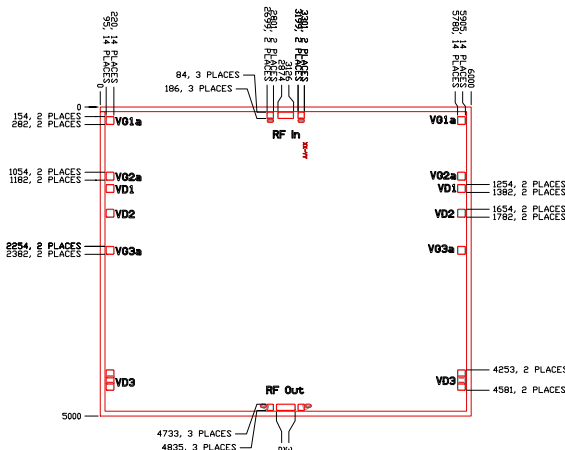
Designator	Description	Quantity
C1,C2,C3,C4,C5,C6,C7,C8,C9,C10	CAP, 51pF, +/-10%, SINGLE LAYER, 0.030", Er 3300, 100V, Ni/Au TERMINATION	10
C11,C12,C13,C14	CAP, 680pF, +/-10%, SINGLE LAYER, 0.070", Er 3300, 100V, Ni/Au TERMINATION	4

Notes:

¹ The input, output and decoupling capacitors should be attached as close as possible to the die- typical distance is 5 to 10 mils with a maximum of 15 mils.

² The MMIC die and capacitors should be connected with 2 mil gold bond wires.

Die Dimensions (units in microns)



Overall die size 5000 x 6000 (+0/-50) microns, die thickness 100 (+/-10) microns.
All Gate and Drain pads must be wire bonded for electrical connection.

Pad Number	Function	Description	Pad Size (in)	Note
1	RF_IN	RF-Input pad. Matched to 50 ohm	102x252	5
2	VG1A bottom	Gate control for stage1. Vg = -2.0 to -3.5 V	128x125	1,2
3	VG1A top	Gate control for stage1. Vg = -2.0 to -3.5 V	128x125	1,2
4	VG2A bottom	Gate control for stage2. Vg = -2.0 to -3.5 V	128x125	1,2
5	VG2A top	Gate control for stage2. Vg = -2.0 to -3.5 V	128x125	1,2
6	VD1 bottom	Drain control for stage1. Vd = 40 V	128x125	1,3
7	VD1 top	Drain control for stage1. Vd = 40 V	128x125	1,3
8	VD2 bottom	Drain control for stage2. Vd = 40 V	128x125	1,4
9	VD2 top	Drain control for stage2. Vd = 40 V	128x125	1,4
10	VG3A bottom	Gate control for stage3. Vg = -2.0 to -3.5 V	128x125	1,2
11	VG3A top	Gate control for stage3. Vg = -2.0 to -3.5 V	128x125	1,2
12	VD3 bottom	Drain control for stage3. Vd = 40 V	328x125	1,4
13	VD3 top	Drain control for stage3. Vd = 40 V	328x125	1,4
14	RF_OUT	RF-Output pad. Matched to 50 ohm	102x302	5

Notes:

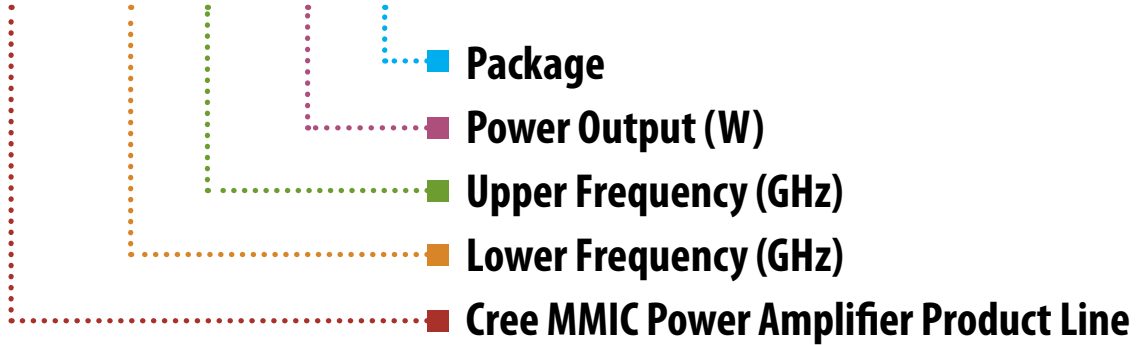
- ¹ Attach bypass capacitor to pads 2-13 per applications circuit
- ² VG1A&2A&3A top and bottom are connected internally, so it would be enough to connect either one for proper operation
- ³ VD1 top and bottom are not connected internally and have to be biased from both sides for proper operation
- ⁴ For current handling, it is recommended to bias VD2 and VD3 from both top and bottom sides
- ⁵ The RF Input and Output pads have a ground-signal-ground with a nominal pitch of 10 mil (250 um). The RF ground pads are 102 x 102 microns

Die Assembly Notes:

- Recommended solder is AuSn (80/20) solder. Refer to Cree's website for the Eutectic Die Bond Procedure application note at <http://www.cree.com/~media/Files/Cree/RF/Application%20Notes/Appnote%20%20Eutectic.pdf>
- Vacuum collet is the preferred method of pick-up.
- The backside of the die is the Source (ground) contact.
- Die back side gold plating is 5 microns thick minimum.
- Thermosonic ball or wedge bonding are the preferred connection methods.
- Gold wire must be used for connections.
- Use the die label (XX-YY) for correct orientation.

Part Number System

CMPA1D1E030D



Parameter	Value	Units
Lower Frequency	13.75	GHz
Upper Frequency ¹	14.5	GHz
Power Output	30	W
Package	Bare Die	-

Table 1.

Note¹: Alpha characters used in frequency code indicate a value greater than 9.9 GHz. See Table 2 for value.

Character Code	Code Value
A	0
B	1
C	2
D	3
E	4
F	5
G	6
H	7
J	8
K	9
Examples:	1A = 10.0 GHz 2H = 27.0 GHz

Table 2.



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